

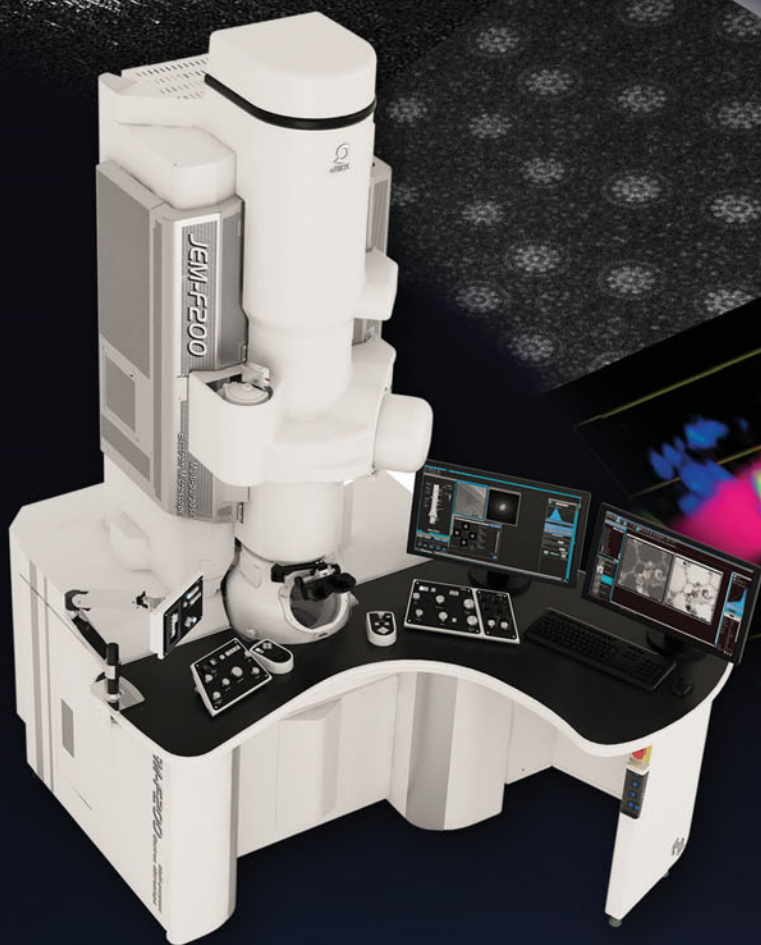
# NO COMPROMISE

## ATOMIC RESOLUTION + FAST ANALYSIS

The New "Go-To" TEM from JEOL

# F2

- Cold FEG boosts probe current
- Fast 3D EDS with dual SDD
- Wide-field STEM-EELS spectrum imaging
- Push-button beam conditions
- Ultra-stable, ultra-fast



10 nm<sup>-1</sup>

2 nm

# JEOL

Solutions for Innovation



[www.jeolusa.com](http://www.jeolusa.com)  
[salesinfo@jeol.com](mailto:salesinfo@jeol.com) • 978-535-5900

Learn more at [www.jeolusa.com/F2](http://www.jeolusa.com/F2)

\*STEM-HAADF image of Quasicrystal • Courtesy of Professor Emeritus K. Hiraga - Tohoku University

H												B	C	N	O	F	Ne
Li	Be																
Na	Mg											Al	Si	P	S	Cl	Ar
K	Ca	Sc	Ti	V	Cr	Mn	Fe	Co	Ni	Cu	Zn	Ga	Ge	As	Se	Br	Kr
Rb	Sr	Y	Zr	Nb	Mo	Tc	Ru	Rh	Pd	Ag	Cd	In	Sn	Sb	Te	I	Xe
Cs	Ba	La	Hf	Ta	W	Re	Os	Ir	Pt	Au	Hg	Tl	Pb	Bi	Po	At	Rn
Fr	Ra	Ac	Rf	Db	Sg	Bh	Hs	Mt	Ds	Rg	Cn	Uut	Fl	Uup	Lv	Uus	Uuo

Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy	Ho	Er	Tm	Yb	Lu
Th	Pa	U	Np	Pu	Am	Cm	Bk	Cf	Es	Fm	Md	No	Lr

# Now Invent.™



THE MATERIALS SCIENCE COMPANY®

catalog: [americanelements.com](http://americanelements.com)

©2001-2014. American Elements is a U.S. Registered Trademark.